

BUREAU OF INDIAN STANDARDS
DRAFT FOR COMMENTS ONLY

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मसौदा भारतीय मानक

इलेक्ट्रॉनिक उपकरणों के लिए कनेक्टर - परीक्षण और माप -
भाग 2- विद्युत निरंतरता और संपर्क प्रतिरोध परीक्षण -
अनुभाग-2 परीक्षण 2बी: संपर्क प्रतिरोध - निर्दिष्ट परीक्षण वर्तमान विधि

Draft Indian Standard

*Connectors for electronic equipment –Tests and
measurements –Part 2-2: Electrical continuity and
contact resistance tests –Test 2b: Contact resistance –
Specified test current method*

ICS 31.220.10

LITD 03 Electromechanical Components And
Mechanical Structures For Electronic--
equipment Sectional Committee

Last date for comments: 25 Dec 2023

NATIONAL FOREWORD

(Formal clauses will be added later)

This draft Indian Standard which is identical to IEC 60512-2-2: 2003 'Connectors for electronic equipment –Tests and measurements – Part 2-2: Electrical continuity and contact resistance tests –Test 2b: Contact resistance – Specified test current method' may be adopted by the Bureau of Indian Standards on the recommendation of the Electromechanical Components And Mechanical Structures For Electronic-equipment Sectional Committee and approval of the Electronics and Information Technology Division Council.

The text of IEC Standard may be approved as suitable for publication as an Indian Standard without deviations. Certain conventions are however not identical to those used in Indian Standards. Attention is particularly drawn to the following:

- a. Wherever the words 'International Standard' appears referring to this standard, they should be read as 'Indian Standard'.
- b. Comma (,) has been used as a decimal marker while in Indian Standards, the current practice is to use a point (.) as the decimal marker.

For the purpose of deciding whether a particular requirement of this standard is complied with, the final value, observed or calculated, expressing the result of a test or analysis, shall be rounded off in accordance with IS 2:2022 'Rules for rounding off numerical values (revised)'. The number of significant places retained in the rounded-off value should be the same as that of the specified value in this standard.

Scope of IEC 60512-2-1:2003 is as follows:

This part of IEC 60512, when required by the detail specification, is used for testing connectors for electronic equipment within the scope of IEC technical committee 48. This test may also be used for similar devices when specified in a detail specification.

The object of this test is to define a standard test method to measure the electrical resistance across a pair of mated contacts or a contact with a measuring gauge.

NOTE:- Technical content of this document has not been enclosed as these are identical to the corresponding IEC Standard, for details please refer IEC 60512-2-2 : 2003 or kindly contact:

Head Electronics & IT Department
Bureau of Indian Standards 9,
B.S. Zafar Marg, New Delhi-110002
Email: litd03@bis.gov.in, litd@bis.gov.in
Tele: 011-23608235